



# Specifications CD4066BMS

## Absolute Maximum Ratings

DC Supply Voltage Range, (VDD) ..... -0.5V to +20V  
 (Voltage Referenced to VSS Terminals)  
 Input Voltage Range, All Inputs ..... -0.5V to VDD +0.5V  
 DC Input Current, Any One Input ..... ±10mA  
 Operating Temperature Range ..... -55°C to +125°C  
 Package Types D, F, K, H  
 Storage Temperature Range (TSTG) ..... -65°C to +150°C  
 Lead Temperature (During Soldering) ..... +265°C  
 At Distance 1/16 ± 1/32 Inch (1.59mm ± 0.79mm) from case for  
 10s Maximum

## Reliability Information

Thermal Resistance .....  $\theta_{ja}$   $\theta_{jc}$   
 Ceramic DIP and FRIT Package ..... 80°C/W 20°C/W  
 Flatpack Package ..... 70°C/W 20°C/W  
 Maximum Package Power Dissipation (PD) at +125°C  
 For TA = -55°C to +100°C (Package Type D, F, K) ..... 500mW  
 For TA = +100°C to +125°C (Package Type D, F, K) ..... Derate  
 Linearity at 12mW/°C to 200mW  
 Device Dissipation per Output Transistor ..... 100mW  
 For TA = Full Package Temperature Range (All Package Types)  
 Junction Temperature ..... +175°C

**TABLE 1. DC ELECTRICAL PERFORMANCE CHARACTERISTICS**

PARAMETER	SYMBOL	CONDITIONS (NOTE 1)		GROUP A SUBGROUPS	TEMPERATURE	LIMITS		UNITS	
						MIN	MAX		
Supply Current	IDD	VDD = 20V, VIN = VDD or GND		1	+25°C	-	0.5	μA	
				2	+125°C	-	50	μA	
		VDD = 18V, VIN = VDD or GND		3	-55°C	-	0.5	μA	
Input Leakage Current	IIL	VC = VDD or GND		1	+25°C	-100	-	nA	
				2	+125°C	-1000	-	nA	
				3	-55°C	-100	-	nA	
Input Leakage Current	IIH	VC = VDD or GND		1	+25°C	-	100	nA	
				2	+125°C	-	1000	nA	
				3	-55°C	-	100	nA	
Input/Output Leakage Current (Switch OFF)	IOZL	VC = 0V, VIS = 18V, VOS = 0V, VIS = 0V, VOS = 18V		VDD = 20	1	+25°C	-100	-	nA
				VDD = 18V	3	+125°C	-1000	-	nA
				VDD = 20	1	-55°C	-100	-	nA
	IOZH			VDD = 20	1	+25°C	-	100	nA
				VDD = 18V	3	+125°C	-	1000	nA
				VDD = 18V	3	-55°C	-	100	nA
On Resistance	RON5	VC = VDD, RL = 10kΩ returned to VDD - VSS/2		VDD = 5V	1	+25°C	1050	-	Ω
	RON10			VDD = 10V	1	+25°C	400	-	Ω
	RON15			VDD = 15V	1	+25°C	240	-	Ω
On Resistance	RON5	VDD = 5V		1, 2	+125°C	-	1300	Ω	
					-55°C	-	800	Ω	
On Resistance	RON10	VDD = 10V		1, 2	+125°C	-	550	Ω	
					-55°C	-	310	Ω	
On Resistance	RON15	VDD = 15V		1, 2	+125°C	-	320	Ω	
					-55°C	-	220	Ω	
Functional (Note 3)	F	VDD = 2.8V, VIN = VDD or GND		7	+25°C	VOH > VDD/2	VOL < VDD/2	V	
		VDD = 20V, VIN = VDD or GND		7	+25°C				
		VDD = 18V, VIN = VDD or GND		8A	+125°C				
		VDD = 3V, VIN = VDD or GND		8B	-55°C				
Switch Threshold RL = 100k to VDD	SWTHR5	VDD = 5V, VC = 1.5V, VIS = GND		1, 2, 3	+25°C, +125°C, -55°C	4.1	-	V	
	SWTHR15	VDD = 15V, VC = 2V, VIS = GND		1, 2, 3	+25°C, +125°C, -55°C	14.1	-	V	
N Threshold Voltage	VNTH	VDD = 10V, ISS = -10μA		1	+25°C	-2.8	-0.7	V	
P Threshold Voltage	VPTH	VSS = 0V, IDD = 10μA		1	+25°C	0.7	2.8	V	

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**TABLE 1. DC ELECTRICAL PERFORMANCE CHARACTERISTICS**

PARAMETER	SYMBOL	CONDITIONS (NOTE 1)	GROUP A SUBGROUPS	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Control Input Low Voltage (Note 2) $ I_{IS}  < 10\mu A$ , $V_{IS} = V_{SS}$ , $V_{OS} = V_{DD}$ and $V_{IS} = V_{DD}$ , $V_{OS} = V_{SS}$	VILC5	VDD = 5V	1, 2, 3	+25°C, +125°C, -55°C	-	1	V
	VILC15	VDD = 15V	1, 2, 3	+25°C, +125°C, -55°C	-	2	V
Control Input High Voltage (Note 2, Figure 2) $V_{IS} = V_{SS}$ and $V_{IS} = V_{DD}$	VIHC	VDD = 5V, $ I_{IS}  = .51mA$ , 4.6V < VOS < 0.4V	1	+25°C	3.5	-	V
		VDD = 5V, $ I_{IS}  = .36mA$ , 4.6V < VOS < 0.4V	2	+125°C	3.5	-	V
		VDD = 5V, $ I_{IS}  = .64mA$ , 4.6V < VOS < 0.4V	3	-55°C	3.5	-	V
	VIHC	VDD = 15V, $ I_{IS}  = 3.4mA$ , 13.5V < VOS < 1.5V	1	+25°C	11	-	V
		VDD = 15V, $ I_{IS}  = 2.4mA$ , 13.5V < VOS < 1.5V	2	+125°C	11	-	V
		VDD = 15V, $ I_{IS}  = 4.2mA$ , 13.5V < VOS < 1.5V	3	-55°C	11	-	V

NOTES: 1. All voltages referenced to device GND, 100% testing being implemented.  
 2. Go/No Go test with limits applied to inputs.  
 3. VDD = 2.8V/3.0V, RL = 100K to VDD  
 VDD = 20V/18V, RL = 10K to VDD

**TABLE 2. AC ELECTRICAL PERFORMANCE CHARACTERISTICS**

PARAMETER	SYMBOL	CONDITIONS	GROUP A SUBGROUPS	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Propagation Delay Signal Input to Signal Output	TPLH TPHL	VC = VDD = 5V, VSS = GND (Notes 2, 3)	9	+25°C	-	40	ns
			10, 11	+125°C, -55°C	-	54	ns
Propagation Delay Turn-On, Turn-Off	TPHZ/ZH TPLZ/ZL	VIS = VDD = 5V (Notes 1, 2)	9	+25°C	-	70	ns
			10, 11	+125°C, -55°C	-	95	ns

NOTES:  
 1. CL = 50pF, RL = 1K, Input TR, TF < 20ns.  
 2. -55°C and +125°C limits guaranteed, 100% testing being implemented.  
 3. CL = 50pF, RL = 200K, Input TR, TF < 20ns.

**TABLE 3. ELECTRICAL PERFORMANCE CHARACTERISTICS**

PARAMETER	SYMBOL	CONDITIONS	NOTES	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Supply Current	IDD	VDD = 5V, VIN = VDD or GND	1, 2	-55°C, +25°C	-	0.25	$\mu A$
				+125°C	-	7.5	$\mu A$
		VDD = 10V, VIN = VDD or GND	1, 2	-55°C, +25°C	-	0.5	$\mu A$
				+125°C	-	15	$\mu A$
		VDD = 15V, VIN = VDD or GND	1, 2	-55°C, +25°C	-	0.5	$\mu A$
				+125°C	-	30	$\mu A$
Control Input Low Voltage $ I_{IS}  < 10\mu A$ , $V_{IS} = V_{SS}$ , $V_{OS} = V_{DD}$ and $V_{IS} = V_{DD}$ , $V_{OS} = V_{SS}$	VILC10	VDD = 10V	1, 2	+25°C, +125°C, -55°C	-	2	V

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**TABLE 3. ELECTRICAL PERFORMANCE CHARACTERISTICS (Continued)**

PARAMETER	SYMBOL	CONDITIONS	NOTES	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Control Input High Voltage (See Figure 2)	VIHC10	VDD = 10V, VIS = VDD or GND	2	+25°C, +125°C, -55°C	7	-	V
Propagation Delay Signal Input to Signal Output	TPLH TPHL	VDD = 10V	1, 2, 3	+25°C	-	20	ns
		VDD = 15V	1, 2, 3	+25°C	-	15	ns
Propagation Delay Turn-On, Turn-Off	TPHZ/ZH TPLZ/ZL	VDD = 10V	1, 2, 3	+25°C	-	40	ns
		VDD = 15V	1, 2, 3	+25°C	-	30	ns
Input Capacitance	CIN	Any Input	1, 2	+25°C	-	7.5	pF

**NOTES:**

1. All voltages referenced to device GND.
2. The parameters listed on Table 3 are controlled via design or process and are not directly tested. These parameters are characterized on initial design release and upon design changes which would affect these characteristics.
3. CL = 50pF, RL = 200K, Input TR, TF < 20ns.

**TABLE 4. POST IRRADIATION ELECTRICAL PERFORMANCE CHARACTERISTICS**

PARAMETER	SYMBOL	CONDITIONS	NOTES	TEMPERATURE	LIMITS		UNITS
					MIN	MAX	
Supply Current	IDD	VDD = 20V, VIN = VDD or GND	1, 4	+25°C	-	25	μA
N Threshold Voltage	VNTH	VDD = 10V, ISS = -10μA	1, 4	+25°C	-2.8	-0.2	V
N Threshold Voltage Delta	ΔVTN	VDD = 10V, ISS = -10μA	1, 4	+25°C	-	±1	V
P Threshold Voltage	VTP	VSS = 0V, IDD = 10μA	1, 4	+25°C	0.2	2.8	V
P Threshold Voltage Delta	ΔVTP	VSS = 0V, IDD = 10μA	1, 4	+25°C	-	±1	V
Functional	F	VDD = 18V, VIN = VDD or GND	1	+25°C	VOH > VDD/2	VOL < VDD/2	V
		VDD = 3V, VIN = VDD or GND					
Propagation Delay Time	TPHL TPLH	VDD = 5V	1, 2, 3, 4	+25°C	-	1.35 x +25°C Limit	ns

- NOTES: 1. All voltages referenced to device GND. 2. CL = 50pF, RL = 200K, Input TR, TF < 20ns. 3. See Table 2 for +25°C limit. 4. Read and Record

**TABLE 5. BURN-IN AND LIFE TEST DELTA PARAMETERS +25°C**

PARAMETER	SYMBOL	DELTA LIMIT
Supply Current - SSI	IDD	±0.1μA
ON Resistance	RONDEL10	± 20% x Pre-Test Reading

**TABLE 6. APPLICABLE SUBGROUPS**

CONFORMANCE GROUP	MIL-STD-883 METHOD	GROUP A SUBGROUPS	READ AND RECORD
Initial Test (Pre Burn-In)	100% 5004	1, 7, 9	IDD, IOL5, IOH5A, RONDEL10
Interim Test 1 (Post Burn-In)	100% 5004	1, 7, 9	IDD, IOL5, IOH5A, RONDEL10
Interim Test 2 (Post Burn-In)	100% 5004	1, 7, 9	IDD, IOL5, IOH5A, RONDEL10
PDA (Note 1)	100% 5004	1, 7, 9, Deltas	
Interim Test 3 (Post Burn-In)	100% 5004	1, 7, 9	IDD, IOL5, IOH5A, RONDEL10
PDA (Note 1)	100% 5004	1, 7, 9, Deltas	

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**TABLE 6. APPLICABLE SUBGROUPS (Continued)**

CONFORMANCE GROUP		MIL-STD-883 METHOD	GROUP A SUBGROUPS	READ AND RECORD
Final Test		100% 5004	2, 3, 8A, 8B, 10, 11	
Group A		Sample 5005	1, 2, 3, 7, 8A, 8B, 9, 10, 11	
Group B	Subgroup B-5	Sample 5005	1, 2, 3, 7, 8A, 8B, 9, 10, 11, Deltas	Subgroups 1, 2, 3, 9, 10, 11
	Subgroup B-6	Sample 5005	1, 7, 9	
Group D		Sample 5005	1, 2, 3, 8A, 8B, 9	Subgroups 1, 2 3

NOTE: 1. 5% Parametric, 3% Functional; Cumulative for Static 1 and 2.

**TABLE 7. TOTAL DOSE IRRADIATION**

CONFORMANCE GROUPS	MIL-STD-883 METHOD	TEST		READ AND RECORD	
		PRE-IRRAD	POST-IRRAD	PRE-IRRAD	POST-IRRAD
Group E Subgroup 2	5005	1, 7, 9	Table 4	1, 9	Table 4

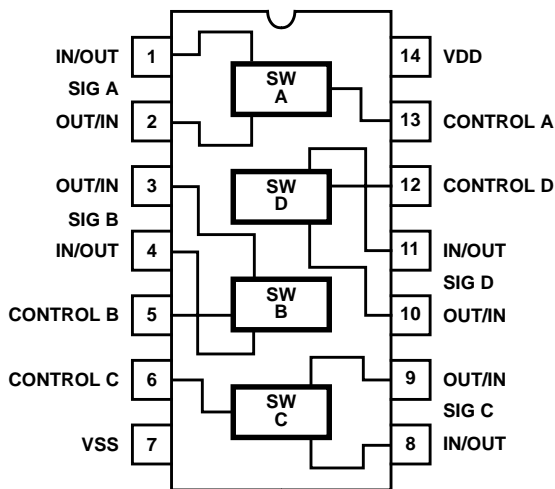
**TABLE 8. BURN-IN AND IRRADIATION TEST CONNECTIONS**

FUNCTION	OPEN	GROUND	VDD	9V ± 0.5V	OSCILLATOR	
					50kHz	25kHz
Static Burn-In 1 (Note 1)	2, 3, 9, 10	1, 4-8, 11-13	14			
Static Burn-In 2 (Note 1)	2, 3, 9, 10	7	1, 4-6, 8, 11-14			
Dynamic Burn-In (Note 1)	-	7	14	2, 3, 9, 10	5, 6, 12, 13	1, 4, 8, 11
Irradiation (Note 2)	2, 3, 9, 10	7	1, 4-6, 8, 11-14			

NOTE:

- Each pin except VDD and GND will have a series resistor of  $10K \pm 5\%$ ,  $VDD = 18V \pm 0.5V$
- Each pin except VDD and GND will have a series resistor of  $47K \pm 5\%$ ; Group E, Subgroup 2, sample size is 4 dice/wafer, 0 failures,  $VDD = 10V \pm 0.5V$

## Functional Diagram



**TRUTH TABLE EACH SWITCH**

TRUTH TABLE EACH SWITCH		
INPUT		OUTPUT
VC	VIS	VOS
1	0	0
1	1	1
0	0	Open
0	1	Open

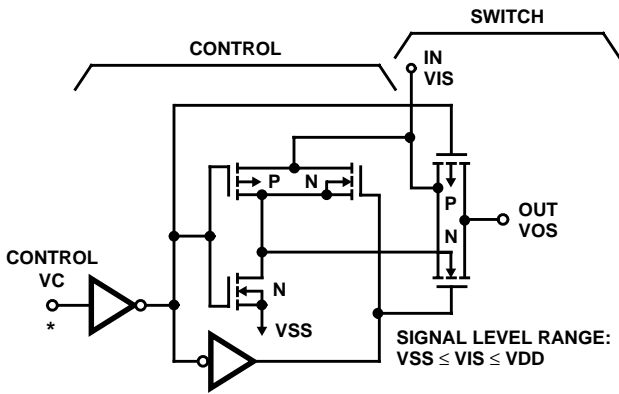
Positive Logic: Switch ON VC = "1"  
Switch OFF VC = "0"

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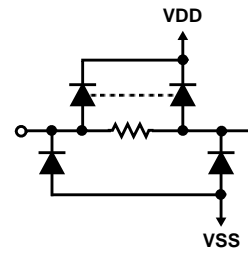
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Schematic



NORMAL OPERATION CONTROL  
LINE BIASING:  
SWITCH ON, VC "1" = VDD  
SWITCH OFF, VC "0" = VSS

\* ALL CONTROL INPUTS ARE  
PROTECTED BY THE CMOS  
PROTECTION NETWORK



NOTE:  
All "P" Substrates  
Connected to VDD

FIGURE 1. SCHEMATIC DIAGRAM OF 1 OF 4 IDENTICAL SWITCHES AND ITS ASSOCIATED CONTROL CIRCUITRY

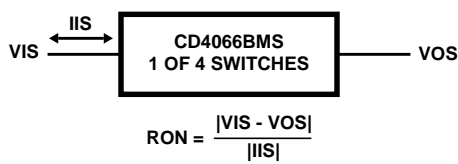


FIGURE 2. DETERMINATION OF RON AS A TEST CONDITION FOR CONTROL INPUT HIGH VOLTAGE (VIHC) SPECIFICATION

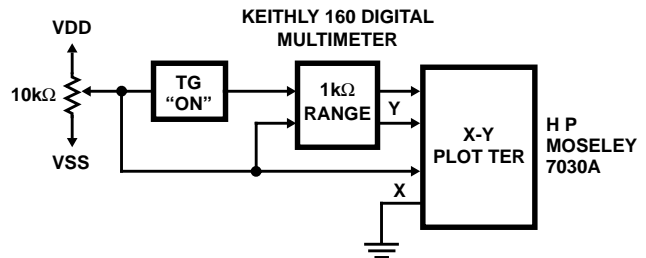


FIGURE 3. CHANNEL ON-STATE RESISTANCE MEASUREMENT CIRCUIT

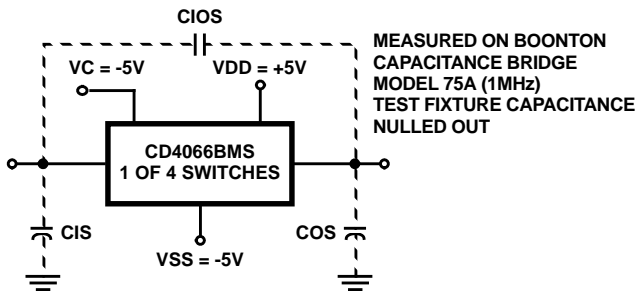


FIGURE 4. CAPACITANCE TEST CIRCUIT

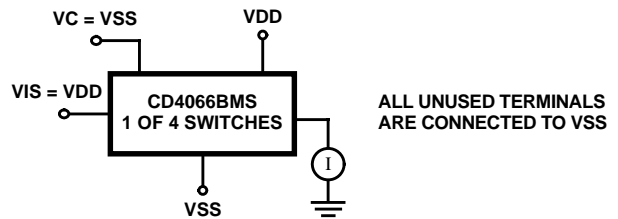


FIGURE 5. OFF SWITCH INPUT OR OUTPUT LEAKAGE

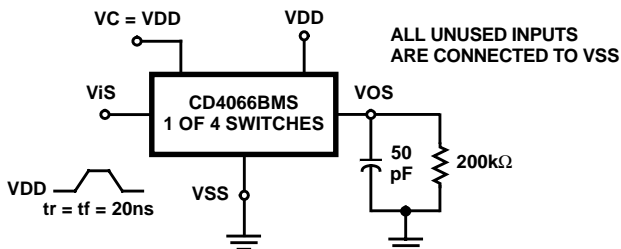


FIGURE 6. PROPAGATION DELAY TIME SIGNAL INPUT (VIS) TO SIGNAL OUTPUT (VOS)

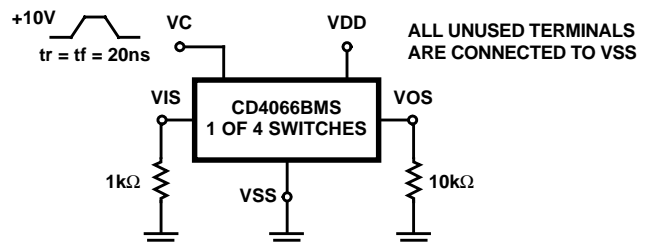


FIGURE 7. CROSSTALK CONTROL INPUT TO SIGNAL OUTPUT

# CD4066BMS

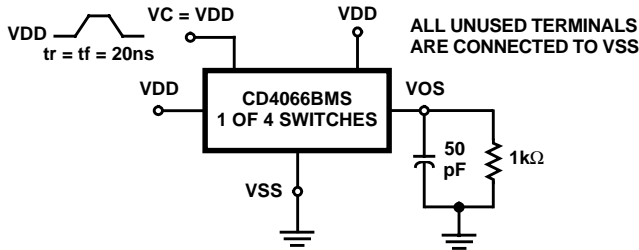
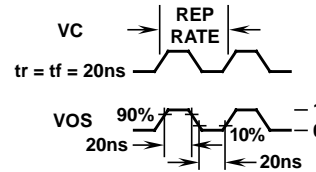


FIGURE 8. PROPAGATION DELAY TPLH, TPHL CONTROL SIGNAL OUTPUT. DELAY IS MEASURED AT VOS LEVEL OF +10% FROM GROUND (TURN ON) OR ON-STATE OUTPUT LEVEL (TURN OFF).

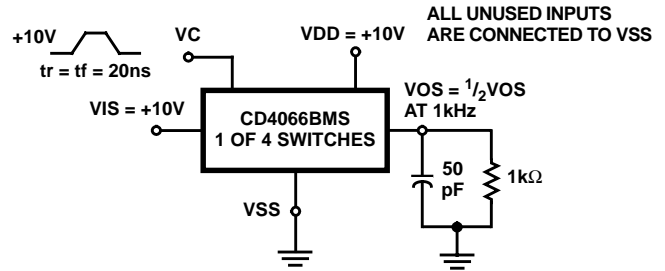


FIGURE 9. MAXIMUM ALLOWABLE CONTROL INPUT REPETITION RATE

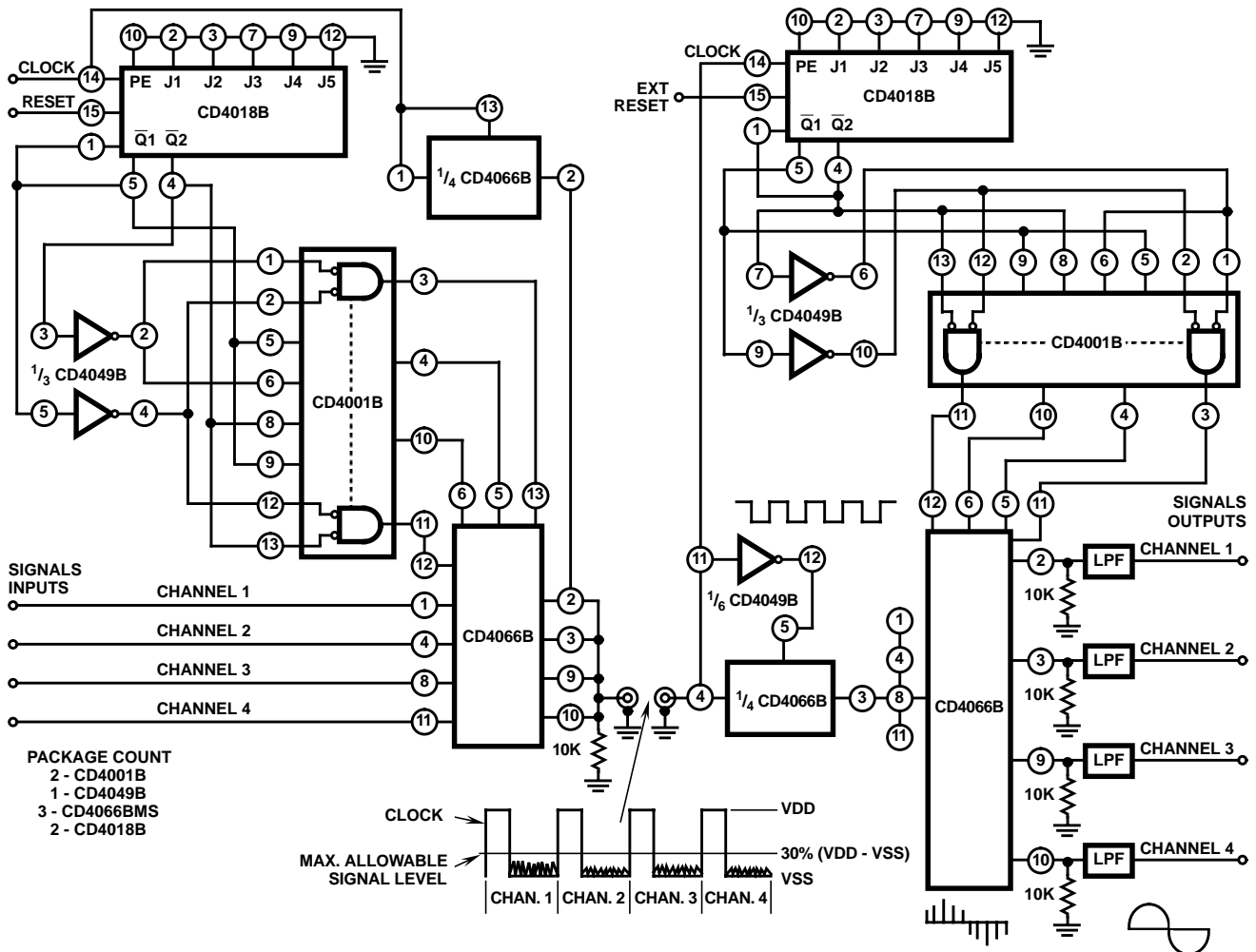


FIGURE 10. 4 CHANNEL PAM MULTIPLEX SYSTEM DIAGRAM

# CD4066BMS

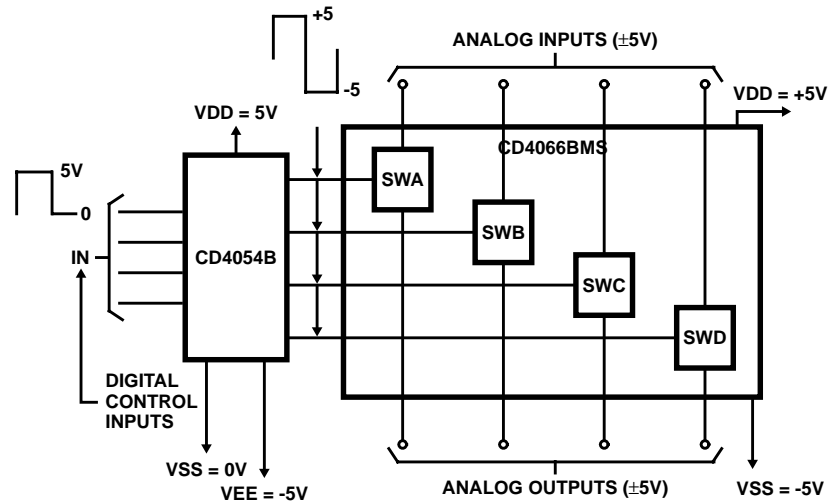


FIGURE 11. BIDIRECTIONAL SIGNAL TRANSMISSION VIA DIGITAL CONTROL LOGIC

## Typical Performance Characteristics

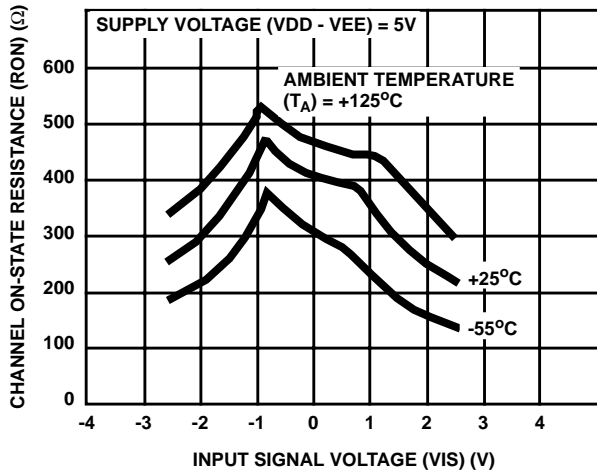


FIGURE 12. TYPICAL ON-STATE RESISTANCE vs INPUT SIGNAL VOLTAGE (ALL TYPES)

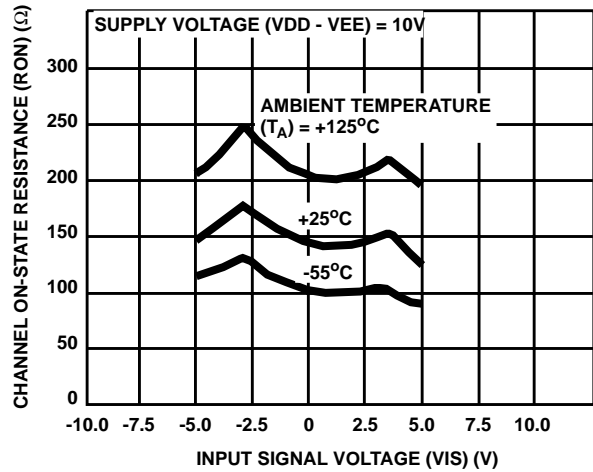


FIGURE 13. TYPICAL ON-STATE vs INPUT SIGNAL VOLTAGE (ALL TYPES).

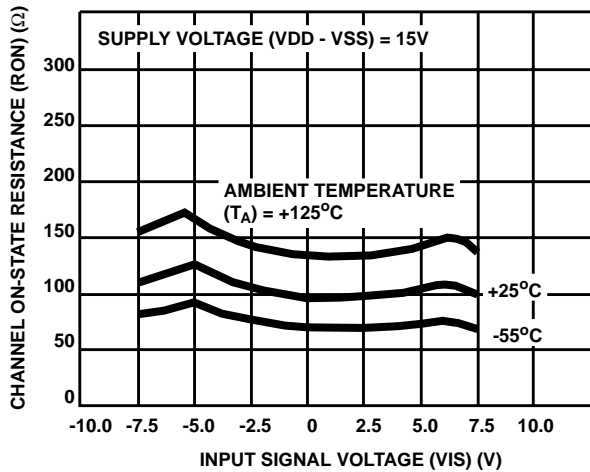


FIGURE 14. TYPICAL ON-STATE RESISTANCE vs INPUT SIGNAL VOLTAGE (ALL TYPES)

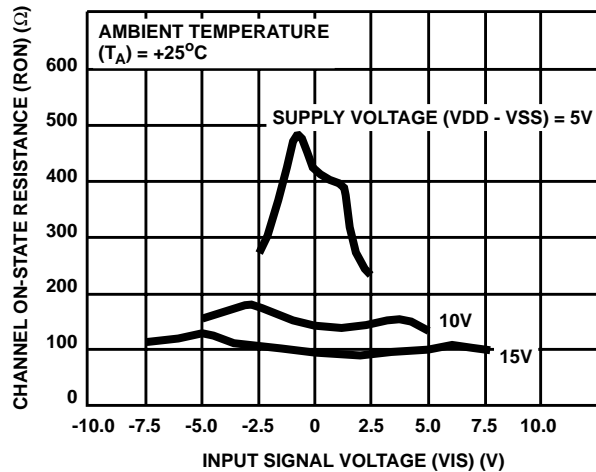


FIGURE 15. ON-STATE RESISTANCE vs INPUT SIGNAL VOLTAGE (ALL TYPES)



